

Technical documentation





SN74ACT240-Q1 SCAS965 - NOVEMBER 2023

SN74ACT240-Q1 Automotive Octal Buffers or Drivers with 3-State Outputs

1 Features

Texas

INSTRUMENTS

- AEC-Q100 qualified for automotive applications:
 - Device temperature grade 1: -40°C to +125°C
 - Device HBM ESD classification level 2
 - Device CDM ESD classification level C4B _
- Available in wettable flank QFN package •
- Wide operating range of 1.5 V to 6 V •
- Inputs accept voltages up to 6 V ٠
- Continuous ±24-mA output drive at 5 V ٠
- Supports up to ±75-mA output drive at 5 V in short bursts
- Drives 50-Ω transmission lines
- Maximum t_{pd} of 9.6 ns at 5 V, 50 pF load ٠

2 Applications

- Handset: smartphone •
- Network switch
- Health and fitness or wearables

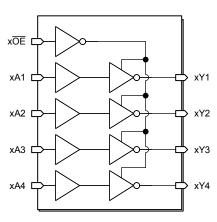
3 Description

The SN74ACT240-Q1 contains eight inverting line drivers with 3-state outputs configured as two banks of four. Each bank has a shared output enable (\overline{OE}) pin.

Package Information

V					
PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾	BODY SIZE ⁽³⁾		
SN74ACT240-Q1	RKS (WQFN, 20)	4.5 mm × 2.5 mm	4.5 mm × 2.5 mm		

- For more information, see Section 11. (1)
- The package size (length × width) is a nominal value and (2)includes pins, where applicable
- (3) The body size (length × width) is a nominal value and does not include pins.



Logic Diagram (Positive Logic)





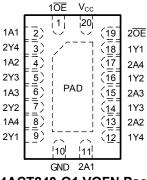
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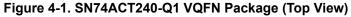
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4 Pin Configuration and Functions





PIN		TYPE ⁽¹⁾	DESCRIPTION	
NAME	NO.		DESCRIPTION	
1 0E	1	I	Output enable 1	
1A1	2	I	1A1 input	
2Y4	3	0	4 output	
1A2	4	I	1A2 input	
2Y3	5	0	2Y3 output	
1A3	6	I	1A3 input	
2Y2	7	0	2Y2 output	
1A4	8	I	1A4 input	
2Y1	9	0	2Y1 output	
GND	10	_	Ground pin	
2A1	11	I	2A1 input	
1Y4	12	0	1Y4 output	
2A2	13	I	2A2 input	
1Y3	14	0	1Y3 output	
2A3	15	I	2A3 input	
1Y2	16	0	1Y2 output	
2A4	17	I	2A4 input	
1Y1	18	0	1Y1 output	
2 0E	19	I	Output enable 2	
VCC	20	_	Power pin	
Thermal pa	ld ⁽²⁾	_	The thermal pad can be connect to GND or left floating. Do not connect to any other signal or supply.	

Table 4-1. Pin Functions

Signal Types: I = Input, O = Output, I/O = Input or Output RKS package only (1)

(2)

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

			MIN	MAX	UNIT
V _{CC}	Supply voltage range		-0.5	7	V
VI	Input voltage range ⁽²⁾		-0.5	V _{CC} + 0.5 V	V
Vo	Output voltage range ⁽²⁾		-0.5	V _{CC} + 0.5 V	V
I _{IK}	Input clamp current	$V_{I} < -0.5 V \text{ or } V_{I} > V_{CC} + 0.5 V$		±20	mA
I _{OK}	Output clamp current	$V_{O} < -0.5 V \text{ or } V_{O}$ > $V_{CC} + 0.5 V$		±50	mA
lo	Continuous output current	$V_{O} = 0$ to V_{CC}		±50	mA
	Continuous output current through V_{CC} or GND			±200	mA
TJ	Junction temperature			150	°C
T _{stg}	Storage temperature		-65	150	°C

(1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute maximum ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If briefly operating outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not sustain damage, but it may not be fully functional. Operating the device in this manner may affect device reliability, functionality, performance, and shorten the device lifetime.

(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

5.2 ESD Ratings

			VALUE	UNIT
	Electrostatic	Human body model (HBM), per AEC Q100-002 HBM ESD Classification Level $2^{(1)}$	±2000	
V _(ESD)	discharge	Charged device model (CDM), per AEC Q100-011 CDM ESD Classification Level C4B	±1000	V

(1) AEC Q100-002 indicate that HBM stressing shall be in with the ANSI/ESDA/JEDEC JS-001 specification.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

Specification	Description	Condition	MIN	MAX	UNIT
V _{CC}	Supply voltage		4.5	5.5	V
V _{IH}	High-level input voltage		2		V
V _{IL}	Low-Level input voltage			0.8	V
VI	Input Voltage	Input Voltage		V _{CC}	V
V _O	Output Voltage	Output Voltage		V _{CC}	V
I _{OH}	High-level output current	High-level output current		-24	mA
I _{OL}	Low-level output current			24	mA
Δt/Δv	Input transition rise or fall rate			20	ns/V
T _A	Operating free-air tempera	ature	-55	125	°C



5.4 Thermal Information

	THERMAL METRIC ⁽¹⁾	RKS (VQFN) 20 PINS	UNIT
R _{0JA}	Junction-to-ambient thermal resistance	67.7	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	72.4	°C/W
R _{0JB}	Junction-to-board thermal resistance	40.4	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	10.3	°C/W
Y _{JB}	Junction-to-board characterization parameter	40.4	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	24.1	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

5.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted); typical values measured at $T_A = 25^{\circ}C$

	TEST CONDITIONS		-40°C	to 125°C		
PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
	1 - 50 114	4.5 V	4.4	4.49		
	I _{OH} = -50 μA	5.5 V	5.4	5.49		
M	I _{OH} = -24 mA	4.5 V	3.9	4.2		V
V _{OH}	I _{OH} = -24 mA	5.5 V	5	5.2		v
	I _{OH} = -50 mA	5.5 V	4.5	4.9		
	I _{OH} = -75 mA	5.5 V	4	4.6		
	I _{OH} = 50 μA	4.5 V		0.01	0.1	
	1 _{0H} – 50 μA	5.5 V		0.01	0.1	
N	I _{OH} = 24 mA	4.5 V		0.2	0.4	V
V _{OL}	I _{OH} = 24 mA	5.5 V		0.2	0.3	v
	I _{OH} = 50 mA	5.5 V		0.3	0.6	
	I _{OH} = 75 mA	5.5 V		0.5	0.9	
I _I	V _I = 5.5 V or GND	0 V to 5.5 V			±1	μA
I _{OZ}	V _O = V _{CC} or GND	5.5 V			±5	μA
I _{CC}	$V_{I} = V_{CC}$ or GND, $I_{O} = 0$	5.5 V			80	μA
ΔI _{CC}	$V_{I} = V_{CC} - 2.1 V$; Any Input	4.5 V to 5.5 V			1.5	mA
Cı	V _I = V _{CC} or GND	5 V		8		pF
Co	V _O = V _{CC} or GND	5 V		14		pF
C _{PD}	F = 1 MHz	5 V		59		pF



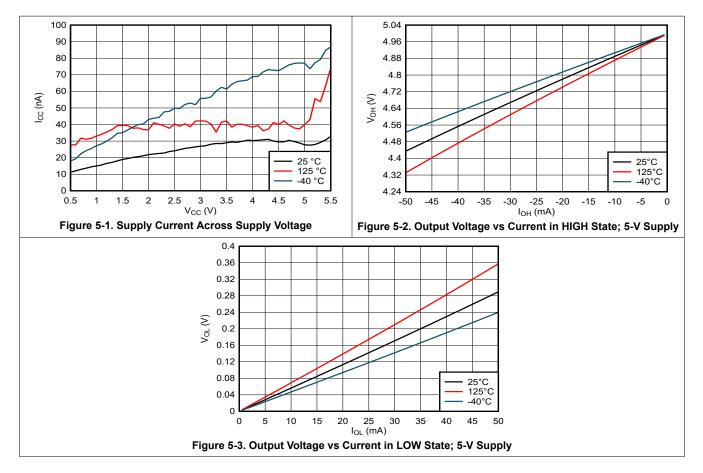
5.6 Switching Characteristics

 C_L = 50 pF; over operating free-air temperature range; typical values measured at T_A = 25°C (unless otherwise noted). See *Parameter Measurement Information*

PARAMETER	FROM (INPUT)		LOAD	V _{cc}	-40°C to 125°C			UNIT
PARAMETER		10 (001901)	TO (OUTPUT) CAPACITANCE		MIN	TYP	MAX	UNIT
t _{PLH}	A	Y	C _L = 50 pF	5 V		4.2	7.1	ns
t _{PHL}	A	Y	C _L = 50 pF	5 V		5	9.6	ns
t _{PZH}	ŌĒ	Y	C _L = 50 pF	5 V		6.3	11.5	ns
t _{PZL}	ŌĒ	Y	C _L = 50 pF	5 V		6.5	11.9	ns
t _{PHZ}	ŌĒ	Y	C _L = 50 pF	5 V		5.3	7.8	ns
t _{PLZ}	ŌĒ	Y	C _L = 50 pF	5 V		3.8	6.3	ns

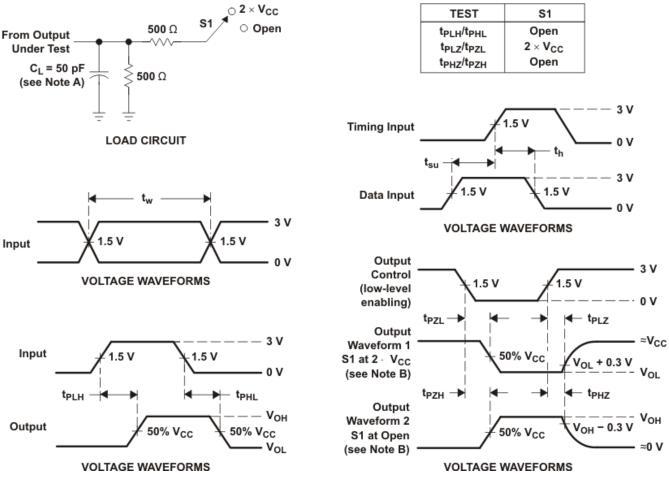
5.7 Typical Characteristics

 $T_A = 25^{\circ}C$ (unless otherwise noted)





6 Parameter Measurement Information



A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z₀ = 50 Ω , t_r \leq 2.5 ns, t_f \leq 2.5 ns.

D. The outputs are measured one at a time with one input transition per measurement.

Figure 6-1. Load Circuit and Voltage Waveforms



7 Detailed Description

7.1 Overview

The SN74ACT240-Q1 devices are organized as two 4-bit buffers or drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes inverted data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

To put the device in the high-impedance state during power up or power down, tie \overline{OE} to V_{CC} through a pullup resistor; the current-sinking capability of the driver determines the minimum value of the resistor.

7.2 Functional Block Diagram

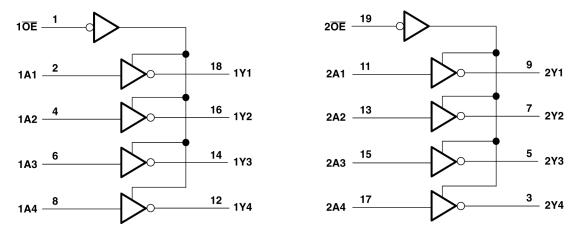


Figure 7-1. Logic Diagram (Positive Logic)

7.3 Feature Description

7.3.1 Balanced CMOS 3-State Outputs

This device includes balanced CMOS 3-state outputs. Driving high, driving low, and high impedance are the three states that these outputs can be in. The term *balanced* indicates that the device can sink and source similar currents. The drive capability of this device may create fast edges into light loads, so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device can drive larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to overcurrent. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

When placed into the high-impedance state, the output will neither source nor sink current, with the exception of minor leakage current as defined in the *Electrical Characteristics* table. In the high-impedance state, the output voltage is not controlled by the device and is dependent on external factors. If no other drivers are connected to the node, then this is known as a floating node and the voltage is unknown. A pull-up or pull-down resistor can be connected to the output to provide a known voltage at the output while it is in the high-impedance state. The value of the resistor will depend on multiple factors, including parasitic capacitance and power consumption limitations. Typically, a $10-k\Omega$ resistor can be used to meet these requirements.

Unused 3-state CMOS outputs should be left disconnected.



7.3.2 TTL-Compatible CMOS Inputs

This device includes TTL-compatible CMOS inputs. These inputs are specifically designed to interface with TTL logic devices by having a reduced input voltage threshold.

TTL-compatible CMOS inputs are high impedance and are typically modeled as a resistor in parallel with the input capacitance given in the *Electrical Characteristics*. The worst case resistance is calculated with the maximum input voltage, given in the *Absolute Maximum Ratings*, and the maximum input leakage current, given in the *Electrical Characteristics*, using Ohm's law ($R = V \div I$).

TTL-compatible CMOS inputs require that input signals transition between valid logic states quickly, as defined by the input transition time or rate in the *Recommended Operating Conditions* table. Failing to meet this specification will result in excessive power consumption and could cause oscillations. More details can be found in the *Implications of Slow or Floating CMOS Inputs* application report.

Do not leave TTL-compatible CMOS inputs floating at any time during operation. Unused inputs must be terminated at V_{CC} or GND. If a system will not be actively driving an input at all times, a pull-up or pull-down resistor can be added to provide a valid input voltage during these times. The resistor value will depend on multiple factors; however, a 10-k Ω resistor is recommended and will typically meet all requirements.

7.3.3 Wettable Flanks

This device includes wettable flanks for at least one package. See the *Features* section on the front page of the data sheet for which packages include this feature.

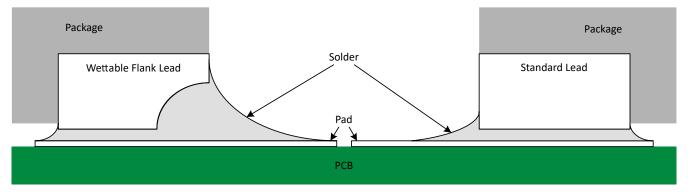


Figure 7-2. Simplified Cutaway View of Wettable-Flank QFN Package and Standard QFN Package After Soldering

Wettable flanks help improve side wetting after soldering, which makes QFN packages easier to inspect with automatic optical inspection (AOI). As shown in Figure 7-2, a wettable flank can be dimpled or step-cut to provide additional surface area for solder adhesion which assists in reliably creating a side fillet. See the mechanical drawing for additional details.

7.3.4 Clamp Diode Structure

As shown in Figure 7-3, the inputs and outputs to this device have both positive and negative clamping diodes.

CAUTION

Voltages beyond the values specified in the *Absolute Maximum Ratings* table can cause damage to the device. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



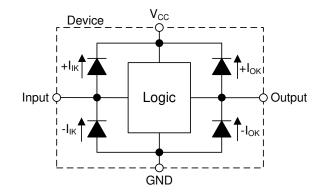


Figure 7-3. Electrical Placement of Clamping Diodes for Each Input and Output

7.4 Device Functional Modes

Table 7-1. Function Table (Each Buffer)				
INPUTS	OUTPUT			
ŌE	Α	Y		
L	Н	L		
L	L	Н		
Н	Х	Z		



8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The SN74ACT240-Q1 can be used to drive signals over relatively long traces or transmission lines. A series damping resistor placed in series with the transmitter's output can be used to reduce ringing caused by impedance mismatches between the driver, transmission line, and receiver. The figure in the *Application Curve* section shows the received signal with three separate resistor values. Just a small amount of resistance can make a significant impact on signal integrity in this type of application.

8.2 Typical Application

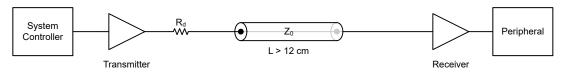


Figure 8-1. Typical Application Block Diagram

8.3 Design Requirements

8.3.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the SN74ACT240-Q1 plus the maximum static supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only source as much current that is provided by the positive supply source. Be sure to not exceed the maximum total current through V_{CC} listed in the *Absolute Maximum Ratings*.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the SN74ACT240-Q1 plus the maximum supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Be sure to not exceed the maximum total current through GND listed in the *Absolute Maximum Ratings*.

The SN74ACT240-Q1 can drive a load with a total capacitance less than or equal to 50 pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 50 pF.

The SN74ACT240-Q1 can drive a load with total resistance described by $R_L \ge V_O / I_O$, with the output voltage and current defined in the *Electrical Characteristics* table with V_{OH} and V_{OL} . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V_{CC} pin.

Total power consumption can be calculated using the information provided in *CMOS Power Consumption and Cpd Calculation*.

Thermal increase can be calculated using the information provided in *Thermal Characteristics of Standard Linear* and Logic (SLL) Packages and Devices.

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CAUTION

The maximum junction temperature, $T_{J(max)}$ listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

8.3.2 Input Considerations

Input signals must cross $V_{IL(max)}$ to be considered a logic LOW, and $V_{IH(min)}$ to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either V_{CC} or ground. The unused inputs can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input will be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The drive current of the controller, leakage current into the SN74ACT240-Q1 (as specified in the *Electrical Characteristics*), and the desired input transition rate limits the resistor size. A 10-k Ω resistor value is often used due to these factors.

The SN74ACT240-Q1 has CMOS inputs and thus requires fast input transitions to operate correctly, as defined in the *Recommended Operating Conditions* table. Slow input transitions can cause oscillations, additional power consumption, and reduction in device reliability.

Refer to the *Feature Description* section for additional information regarding the inputs for this device.

8.3.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the V_{OL} specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V_{CC} or ground.

Refer to the *Feature Description* section for additional information regarding the outputs for this device.



8.4 Detailed Design Procedure

- Add a decoupling capacitor from V_{CC} to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V_{CC} and GND pins. An example layout is shown in the *Layout* section.
- 2. Ensure the capacitive load at the output is ≤ 50 pF. This is not a hard limit; by design, however, it will optimize performance. This can be accomplished by providing short, appropriately sized traces from the SN74ACT240-Q1 to one or more of the receiving devices.
- 3. Ensure the resistive load at the output is larger than $(V_{CC} / I_{O(max)}) \Omega$. Doing this will prevent the maximum output current from the *Absolute Maximum Ratings* from being violated. Most CMOS inputs have a resistive load measured in M Ω ; much larger than the minimum calculated previously.
- 4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, *CMOS Power Consumption and Cpd Calculation*.

8.5 Application Curve

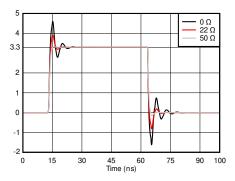


Figure 8-2. Simulated Signal Integrity at the Receiver with Different Damping Resistor (R_d) Values



8.6 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

8.7 Layout

8.7.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

8.7.2 Layout Example

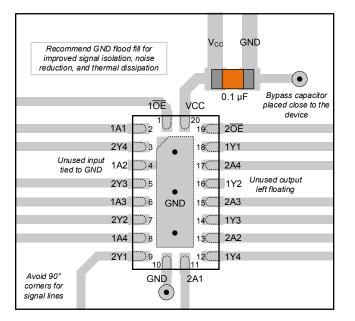


Figure 8-3. Example Layout for the SN74ACT240-Q1



9 Device and Documentation Support

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.3 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

DATE	REVISION	NOTES
November 2023	*	Initial Release

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
SN74ACT240QWRKSRQ1	ACTIVE	VQFN	RKS	20	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	ACT240Q	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF SN74ACT240-Q1 :



17-Dec-2023

• Catalog : SN74ACT240

Military : SN54ACT240

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications



www.ti.com

TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74ACT240QWRKSRQ1	VQFN	RKS	20	3000	180.0	12.4	2.8	4.8	1.2	4.0	12.0	Q1



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PACKAGE MATERIALS INFORMATION

18-Dec-2023



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74ACT240QWRKSRQ1	VQFN	RKS	20	3000	210.0	185.0	35.0

PW0020A



PACKAGE OUTLINE

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



PW0020A

EXAMPLE BOARD LAYOUT

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



PW0020A

EXAMPLE STENCIL DESIGN

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



RKS 20

2.5 x 4.5, 0.5 mm pitch

GENERIC PACKAGE VIEW

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





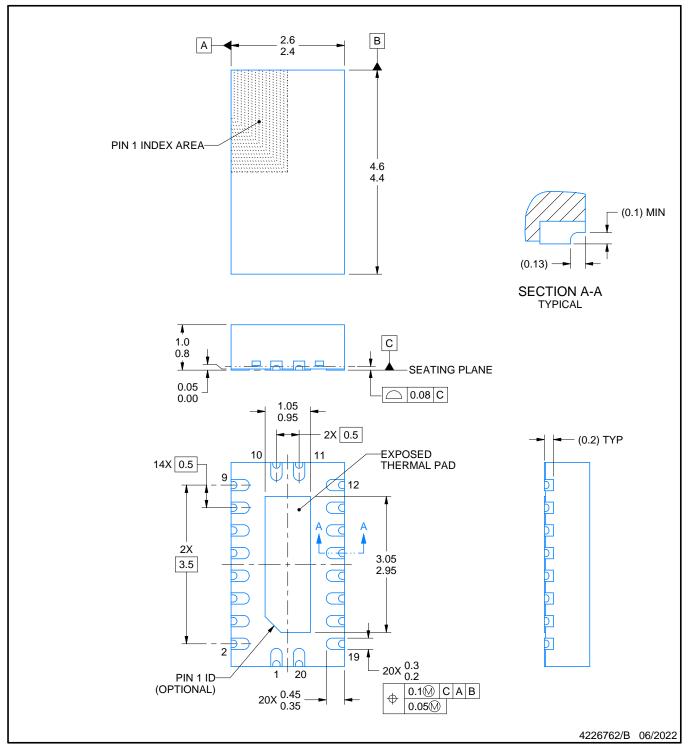
RKS0020B



PACKAGE OUTLINE

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

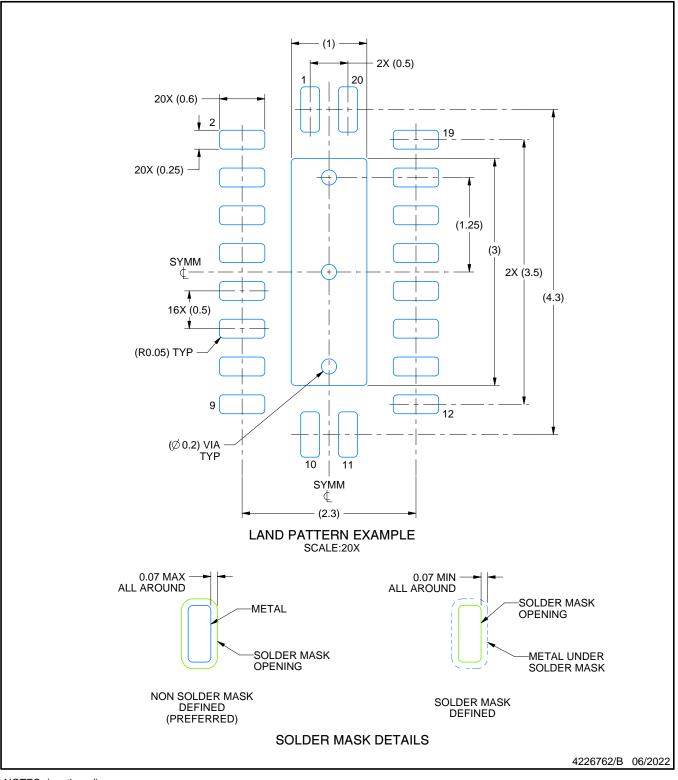


RKS0020B

EXAMPLE BOARD LAYOUT

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

5. Vias are optional depending on application, refer to device data sheet. If some or all are implemented, recommended via locations are shown.

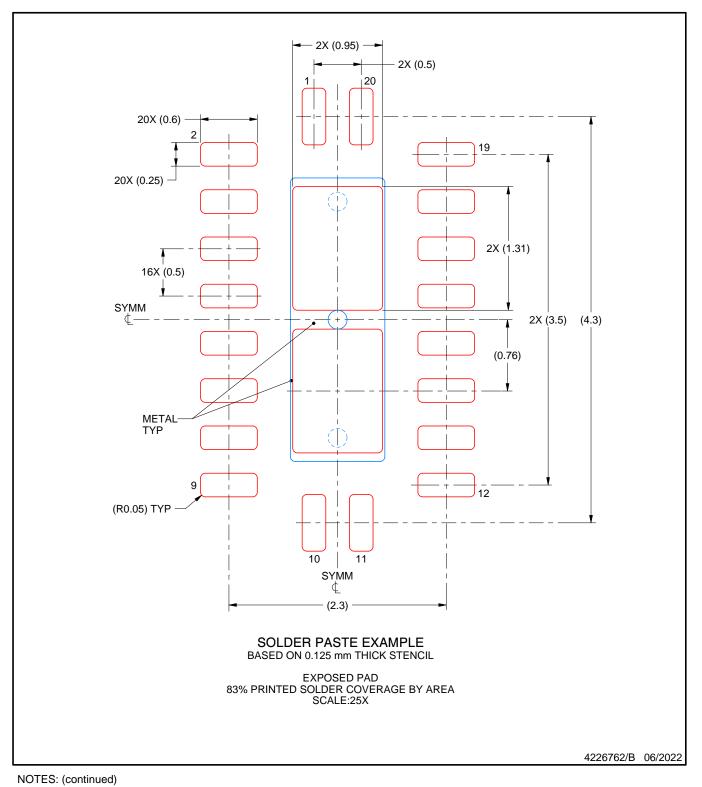


RKS0020B

EXAMPLE STENCIL DESIGN

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



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